

**Design error localization in digital circuits by stuck-at fault test patterns**

**Jutman, Artur; Ubar, Raimund-Johannes** [MIEL] 2000 : 22nd International Conference on Microelectronics : Niš, Yugoslavia, 14-17 May 2000 : proceedings. Volume 2 2000 / p. 723-726 <https://ieeexplore.ieee.org/document/838792>